KAMAYA	онм ———		
	•••••	Drawing No.: Date:	MLP-K-HTS-0003 /1 2025. 1. 22
	Data s	shoot	
Title: M	IETAL-PLATE CHIP F	RESISTOR; LC	OM OHM
Style: M	ILP20,63		
	AEC-Q200	qualified	
	RoHS COMPL Halogen and A		
Note:	 Stock conditions Temperature: +5°C ~ +35°C Relative humidity: 25% ~ 75% The period of guarantee: Within Solder Product specification container are subject to change at any If you have any questions or agreement is necessary, plear 	erability shall be satisfie ed in this data sheet time without notice a Purchasing Specifie	ed. cation for any quality
		釜屋電機 KAMAYA ELI	株式會社

Hokkaido Research Center Approval by: T. Sannomiya Drawing by: M. Shibuya

Title:	METAL-PLATE CHIP RESISTOR; LOW OHM
	MLP20, 63

Page: 1/9

1. Scope

1.1 This data sheet covers the detail requirements for metal-plate chip resistor ; low ohm, style of MLP20, 63.

1.2 Applicable documents

JIS C 5201-1: 2011, IEC60115-1: 2008, AEC-Q200 Rev.D

2. Classification

Type designation shall be the following form.

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(Example)	MLP	63	К	R010	F	TE
	1	2	3	4	5	6
	Sty	le				
1	Metal - plat	e chip re	sistor; low ohi	n —	Style	
2	Size					
	Μ	LP20	2012 size			
	Μ	LP63	6332 size			

3 Temperature coefficient of resistance				
	Ν	±70×10 ⁻⁶ / °C		
	К	±100×10 ⁻⁶ / °C		

4 Rated resistance

1L50	1.5mΩ
R002	2mΩ

5 Tolerance on rated resistance

F	±1%
J	±5%

6 Packaging form

TP	Paper taping
TE	Embossed taping

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Title: METAL-PLATE CHIP RESISTOR; LOW OHM MLP20, 63

Drawing No: MLP-K-HTS-0003 /1

Page: 2/9

3. Rating

3.1 The ratings shall be in accordance with Table-1.

			Table-1				
Style	Rated dissipation	Rated current	Temperature coefficient of		Rated resistance	Tolerance on rated	
Otyle	(W)	(A)	resistance	(10 ⁻ 6/ °C)	(mΩ)	resistance	
MLP20	1.0	10	K	100	10		
IVILF20	1.0	10	Ν	±70	IU		
		31.6	К	100	2		
		51.0	N	±70	2		
		25.0	K	100	3		
		25.8	Ν	±70	3		
		22.3	K	100	4		
		22.3	Ν	±70	4	F(±1%) J(±5%)	
		20	K	100	5		
		20	Ν	±70			
MLP63	2.0	18.2	K	100	6		
	2.0	10.2	Ν	±70	0		
		16.9	K	100	7		
		10.9	Ν	±70	I		
		15.8	K	100	8		
		15.0	Ν	±70	0		
		14.9	К	100	9		
		14.9	Ν	±70	5		
		14.1	К	100	10		
		14.1	Ν	±70	IU		

Style	Insulation voltage (V)	Category temperature range (°C)
MLP20	100	EE 165
MLP63	100	-55~+155

3.2 Derating

The derated values of dissipation at temperature in excess of 70 °C shall be as indicated by the following curve.



Figure-1 Derating curve

3.3 Rated voltage

d.c. or a.c. r.m.s. voltage calculated from the square root of the product of the rated resistance and the rated dissipation.

$$E = \sqrt{P \cdot R}$$

$$E : Rated voltage (V)$$

$$P: Rated dissipation (W)$$

$$R: Rated resistance (\Omega)$$

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Title: METAL-PLATE CHIP RESISTOR; LOW OHM MLP20, 63

Page: 3/9

3.4 Rated current

The rated current calculated from the square root of the quotient of the rated resistance and the rated dissipation.

$$I = \sqrt{P / R}$$

I: Rated current (A) P: Rated dissipation (W) R: Rated resistance (Ω)

The rated current shall be corresponding to rated voltage.

4. Packaging form

The standard packaging form shall be in accordance with Table-2.

	Iadie-2					
Symbol	Packaging form		Packaging form		Standard packaging quantity / units	Application
TP	Paper taping	8mm width, 4mm pitches	5,000 pcs.	MLP20		
TE	Embossed taping	12mm width, 4mm pitches	4,000 pcs.	MLP63		

T-1-1- 0

5. Dimensions

5.1 The resistor shall be of the design and physical dimensions in accordance with Figure-2 and Table-3.



	Table-3					Unit: mm			
Style	Rated resistance (m Ω)	L	W	Н	С	d			
MLP20	10	2.0±0.15	1.25±0.15	0.22±0.10	0.33±0.15	0.47±0.20			
	2			0.58±0.15					
	3		0.45±0.15	2.2±0.25	2.2±0.25				
	4			0.34±0.15					
	5			0.51±0.15	1.1±0.25	1.1±0.25			
MLP63	6	6.3±0.25	3.1±0.25	0.5±0.15					
	7				0.5±0.15	0.6±0.25	0.6±0.25		
	8								1.1±0.25
	9			0.35±0.15	0.8±0.25	0.8±0.25			
	10			0.5±0.25	0.5±0.25				

5.2 Net weight (Reference)

Style	Rated resistance (m Ω)	Net weight (mg)
MLP20	10	3
MLP63	2 to 10	60

Product specification contained in this data sheet are subject to change at any time without notice.

Title:	METAL-PLATE CHIP RESISTOR; LOW OHM
	MLP20, 63

Page: 4/9

6. Marking

6.1 MLP63

The rated resistance shall be marked in 4 characters consisting of 3 figures and a letter and marked on over coat side.

 $\begin{array}{ll} (\text{Example}) & \text{``R010''} \rightarrow 0.01 \ [\Omega] \rightarrow 10 \ [\text{m}\Omega] \\ & \text{``1L50''} \rightarrow 0.0015 \ [\Omega] \rightarrow 1.5 \ [\text{m}\Omega] \end{array}$

6.2 MLP20

The rated resistance shall be marked in combination of two figures and underlines and marked on over coat side.

 $\begin{array}{ll} (\text{Example}) & \underbrace{``05"}{} \rightarrow 0.005 \ [\Omega] \rightarrow 5 \ [\text{m}\Omega] \\ & \underbrace{``10"}{} \rightarrow 0.01 \ [\Omega] \rightarrow 10 \ [\text{m}\Omega] \end{array}$

Title: METAL-PLATE CHIP RESISTOR; LOW OHM MLP20, 63

Page: 5/9

7. Performance

7.1 The standard condition for tests shall be in accordance with Sub-clause 4.2, JIS C 5201–1: 2011.

7.2 The performance shall be satisfied in Table-4.

	i ne performance snall be saus	Table-4(1)	
No	Test items	Condition of test	Performance requirements
1	High temperature exposure AEC Q200 - No.3	MIL-STD-202 Method 108 Ambient temperature:155 \pm 2°C, Condition: Without load, Duration: 1,000 $^{+48}_{0}$ h Interval measurements: 250 h and 500 h	Δ R/R: Within ±3% No visible damage
2	Temperature cycling AEC Q200 - No.4	JESD22 Method JA-104 Temperature: -55±3°C / 125±2°C, Dwell time: 30min maximum at each temp. Transition time: 1 min. max. Number of cycles: 1,000 cycles. Interval measurements: 250 cy and 500 cy	Δ R/R: Within ±3% No visible damage
3	Bias humidity AEC Q200 – No.7	 MIL-STD-202 Method 103 Condition: 85°C & 85% R.H. Test power: 10% of rated power shall be applied for continuously. Duration: 1,000 ⁺⁴⁸/₀ h Interval measurements: 250 h and 500 h 	∆R/R: Within ±3% No visible damage
4	Operational life AEC Q200 – No.8	MIL-STD-202 Method 108 Ambient temperature: $125\pm2^{\circ}$ C The applied voltage shall be the voltage to be calculated at 35% of rated dissipation or the limiting element voltage whichever is the smaller. Condition: The voltage shall be applied for continuously. Duration: 1,000 $^{+48}_{0}$ h Interval measurements: 250 h and 500 h	∆R/R: Within ±3% No visible damage
5	External Visual AEC Q200 – No.9	MIL-STD-883 Method 2009	Inspect device construction, marking and workmanship.
6	Dimensions AEC Q200 – No.10	JESD22 Method JB-100	As in Table-3
7	Resistance to Solvents AEC Q200 – No.12	MIL-STD-202 Method 215 Solvent: 2–propanol at 25 °C Immersion time: 3 min Brush: 10 times brushing Immersion and brush cycle: 3cycle	∆R/R: Within ±1% No visible damage
8	Mechanical Shock AEC Q200 – No.13	MIL-STD-202 Method 213 Waveform: half sine, Peak value100G, Normal duration 6ms Condition: XX'YY'ZZ', 18times total	∆R/R: Within ±1% No visible damage

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Drawing No: MLP–K–HTS–0003 /1

Title: METAL-PLATE CHIP RESISTOR; LOW OHM MLP20, 63

Page: 6/9

Table-4(2)					
No	Test items	Condition of test	Performance requirements		
9	Vibration AEC Q200 – No.14	MIL-STD-202 Method 204 Peak acceleration and Sweep time: 5 g's for 20 min , Frequency 10Hz to 2000Hz, Condition: 12 cycles each of 3 orientations	Δ R/R: Within \pm 1% No visible damage		
10	Resistance to soldering heat AEC Q200 - No.15	MIL-STD-202 Method 210 Test conditions:K Temperature: 250±5 °C Time: 30sec Temperature ramp: 1°C/s-4°C/s immersion and emersion rate : Time above 183°C, 90 s - 120 s The assembly shall be exposed to three heat cycles.	∆R/R: Within ±3% No visible damage		
11	ESD test AEC Q200 – No.17	AEC-Q200-002 Human body model, 2 Kohm, 150 pF, Test voltage: 12kV	Δ R/R: Within \pm 5% No visible damage		
12	Solderability AEC Q200 – No.18	J-STD-002 B) Bake the sample for 155 °C dwell time 4h / solder dipping 235°C/ 5s. Solder: Sn96.5-Ag3-Cu0.5 B1) Bake the sample for 155 °C dwell time 4h / solder dipping 245°C/ 5s. Solder: Sn96.5-Ag3-Cu0.5 D) Category 3, Solder dipping 260°C/ 30s.	The surface of terminal immersed shall be min. of 95% covered with a new coating of solder.		
13	Electrical Characterization AEC Q200 - No.19	1. D.C. Resistance Conform to JIS C 5201-1 4.5 Mount it on our recommended 4-terminal test board and measure the resistance using the 4-terminal measurement method. Current Current Voltage terminal Style Resistance value(mΩ) A MLP63 2 to 4 5 to 10 4.0 1.8 2. Temperature Coefficient of Resistance -55 °C / +20°C +20 °C / +155°C	 The resistance value shall correspond with the rated resistance taking into account the specified tolerance. As in Table–1 		
14	Flammability AEC Q200 – No.20	UL-94	V-1 is acceptable		
15	Bending strength AEC Q200 – No.21	AEC-Q200-005 Bending value2mm Holding time: 60sec.	Δ R/R: Within ±1% No visible damage		
16	Adhesion AEC Q200 – No.22	AEC-Q200-006 Pressurizing force:17.7N Test time: 60±1s.	Δ R/R: Within \pm 1% No visible damage		

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Page: 7/9

8. Taping

8.1 Applicable documents JIS C 0806–3: 2014, EIAJ ET–7200C: 2010

8.2 Taping dimensions

8.2.1 Paper taping (8mm width, 4mm pitches)

Taping dimensions shall be in accordance with Figure-3 and Table-5.



8.2.2 Embossed taping (12mm width, 4mm pitches)

Taping dimensions shall be in accordance with Figure-4 and Table-6.



Product specification contained in this data sheet are subject to change at any time without notice.

Title: METAL-PLATE CHIP RESISTOR; LOW OHM MLP20, 63

Page: 8/9

- 1). The cover tapes shall not cover the sprocket holes.
- 2). Tapes in adjacent layers shall not stick together in the packing.
- 3). Components shall not stick to the carrier tape or to the cover tape.
- 4). Pitch tolerance over any 10 pitches ±0.2mm.
- 5). The peel strength of the top cover tape shall be with in 0.1N to 0.5N on the test method as shown in the following MLP20: Figure–5, MLP63: Figure–6.
- 6). When the tape is bent with the minimum radius for (MLP20: 25mm, MLP63 : 30mm) the tape shall not be damaged and the components shall maintain their position and orientation in the tape.
- 7). In no case shall there be two or more consecutive components missing.

The maximum number of missing components shall be one or 0.1%, whichever is greater.







Figure-6

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KAMAYA OHM Title: METAL-PLATE CHIP

Page: 9/9

/1

MLP-K-HTS-0003

Drawing No:

8.3 Reel dimension

Reel dimensions shall be in accordance with the following Figure–7 and Table–7. Plastic reel (Based on EIAJ ET–7200C)



Note : Marking label shall be marked on a place of Marking A or two place of Marking A and B.

8.4 Leader and trailer tape.



9. Marking on package

The label of a minimum package shall be legibly marked with follows.

9.1 Marking A

(1) Classification

(Style, Temperature coefficient of resistance, Rated resistance, Tolerance on rated resistance, Packaging form)

(2) Lot number (3) Quantity (4) Manufacturer's name or trade mark (5) Others

9.2 Marking B (KAMAYA Control label)

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